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May 2015

FDS86267P

P-Channel Shielded Gate PowerTrench® MOSFET

-150 V, -2.2 A, 255 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 255 m Ω at V_{GS} = -10 V, I_D = -2.2 A
- Max $r_{DS(on)} = 290 \text{ m}\Omega$ at $V_{GS} = -6 \text{ V}$, $I_D = -2 \text{ A}$
- Very Low r_{DS(on)} Mid Voltage P-channel Silicon Technology Optimised for Low Qg
- This Product is Optimised for Fast Switching Applications as well as Load Switch Applications
- 100% UIL Tested
- RoHS Compliant

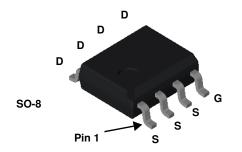


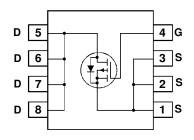
General Description

This P-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates shielded gate technology. The process has been optimized for the on-state resistance and yet maintain superior switching performance.

Applications

- Active Clamp Switch
- Load Switch





MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted.

| Symbol | Parameter | | | Ratings | Units | |
|-------------------|--|------------------------|-----------|-------------|-------|--|
| V_{DS} | Drain to Source Voltage | | | -150 | V | |
| V_{GS} | Gate to Source Voltage | | | ±25 | V | |
| | Drain Current -Continuous | | (Note 1a) | -2.2 | Α | |
| ID | -Pulsed | | (Note 4) | -34 | A | |
| E _{AS} | Single Pulse Avalanche Energy | | (Note 3) | 54 | mJ | |
| В | Power Dissipation | T _A = 25 °C | (Note 1a) | 2.5 | W | |
| P_{D} | Power Dissipation | T _A = 25 °C | (Note 1b) | 1.0 | | |
| T_J , T_{STG} | Operating and Storage Junction Temperature Ran | nge | | -55 to +150 | °C | |

Thermal Characteristics

| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | (Note 1a) | 50 | °C/W |
|-----------------|---|-----------|-----|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | (Note 1b) | 125 | C/VV |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|-----------|---------|-----------|------------|------------|
| FDS86267P | FDS86267P | SO-8 | 13 " | 12 mm | 2500 units |

Electrical Characteristics $T_J = 25$ °C unless otherwise noted.

| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Units |
|---------------------------------------|--|---|------|------|------|-------|
| Off Chara | acteristics | | | | | |
| BV _{DSS} | Drain to Source Breakdown Voltage | $I_D = -250 \mu A, V_{GS} = 0 V$ | -150 | | | V |
| ΔBV _{DSS} ΔT _J | Breakdown Voltage Temperature Coefficient | I_D = -250 μ A, referenced to 25 °C | | -121 | | mV/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = -120 V, V _{GS} = 0 V | | | -1 | μΑ |
| I _{GSS} | Gate to Source Leakage Current | V _{GS} = ±25 V, V _{DS} = 0 V | | | ±100 | nA |

On Characteristics

| $V_{GS(th)}$ | Gate to Source Threshold Voltage | $V_{GS} = V_{DS}$, $I_D = -250 \mu A$ | -2 | -3 | -4 | ٧ |
|--|--|--|----|-----|-----|-------|
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate to Source Threshold Voltage Temperature Coefficient | I_D = -250 μ A, referenced to 25 °C | | 5 | | mV/°C |
| r _{DS(on)} | Static Drain to Source On Resistance | $V_{GS} = -10 \text{ V}, I_D = -2.2 \text{ A}$ | | 191 | 255 | |
| | | $V_{GS} = -6 \text{ V}, I_D = -2 \text{ A}$ | | 214 | 290 | mΩ |
| | | $V_{GS} = -10 \text{ V}, I_D = -2.2 \text{ A}, T_J = 125 \text{ °C}$ | | 342 | 448 | 1 |
| 9 _{FS} | Forward Transconductance | $V_{DS} = -10 \text{ V}, I_{D} = -2.2 \text{ A}$ | | 6.8 | | S |

Dynamic Characteristics

| C _{iss} | Input Capacitance | V 75 V V 0 V | | 806 | 1130 | pF |
|------------------|------------------------------|---|-----|-----|------|----|
| Coss | Output Capacitance | $V_{DS} = -75 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz | | 54 | 75 | pF |
| C _{rss} | Reverse Transfer Capacitance | 1 - 1 101112 | | 1.6 | 2.3 | pF |
| R_q | Gate Resistance | | 0.1 | 3 | 6 | Ω |

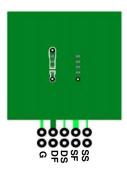
Switching Characteristics

| t _{d(on)} | Turn-On Delay Time | | 9.7 | 20 | ns |
|---------------------|-------------------------------|--|-----|----|----|
| t _r | Rise Time | V _{DD} = -75 V, I _D = -2.2 A, | 2.5 | 10 | ns |
| t _{d(off)} | Turn-Off Delay Time | $V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$ | 17 | 30 | ns |
| t _f | Fall Time | | 5.7 | 12 | ns |
| Q _a | Total Gate Charge | V _{GS} = 0 V to -10 V | 11 | 16 | nC |
| Q_{q} | Total Gate Charge | $V_{GS} = 0 \text{ V to -6 V} V_{DD} = -75 \text{ V},$ | 7 | 10 | nC |
| Q_{gs} | Gate to Source Charge | I _D = -2.2 A | 3.2 | | nC |
| Q_{ad} | Gate to Drain "Miller" Charge | | 1.9 | | nC |

Drain-Source Diode Characteristics

| V _{SD} Source-Drain Diode Forward Voltage | Source Drain Diede Ferward Voltage | $V_{GS} = 0 \text{ V}, I_S = -2.2 \text{ A}$ (Note 2) | -0.8 | -1.3 | W |
|--|---|---|------|------|----|
| | $V_{GS} = 0 \text{ V}, I_{S} = -2 \text{ A}$ (Note 2) | -0.8 | -1.2 | v | |
| t _{rr} | Reverse Recovery Time | I _F = -2.2 A, di/dt = 100 A/μs | 65 | 104 | ns |
| Q _{rr} | Reverse Recovery Charge | 1F = -2.2 A, α//αι = 100 A/μs | 157 | 251 | nC |

^{1.} R_{0.JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0.JC} is guaranteed by design while R_{0.CA} is determined by the user's board design.



a) 50 °C/W when mounted on a 1 in² pad of 2 oz copper.



b) 125 °C/W when mounted on a minimum pad.

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%. 3. Starting T $_J$ = 25 °C, L = 3 mH, I $_{AS}$ = -6 A, V $_{DD}$ = -150 V, V $_{GS}$ = -10 V. 100% tested at L = 0.3 mH, I $_{AS}$ = -13 A.
- 4. Pulsed Id please refer to Fig 11 SOA graph for more details.

Typical Characteristics T_{.1} = 25 °C unless otherwise noted

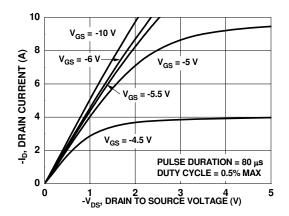


Figure 1. On Region Characteristics

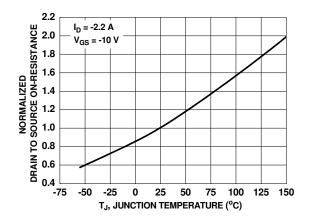


Figure 3. Normalized On Resistance vs Junction Temperature

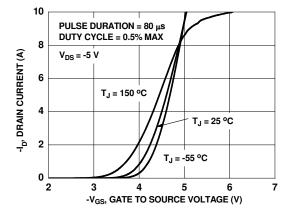


Figure 5. Transfer Characteristics

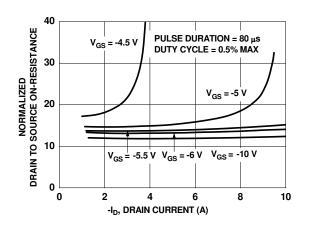


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

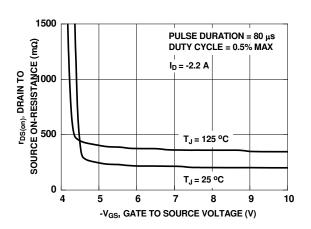


Figure 4. On-Resistance vs Gate to Source Voltage

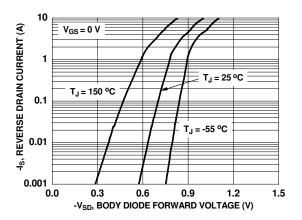


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

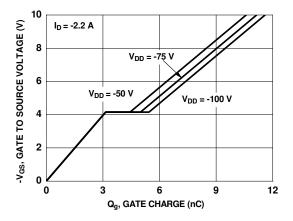


Figure 7. Gate Charge Characteristics

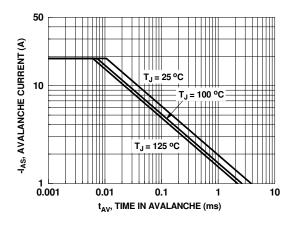


Figure 9. Unclamped Inductive Switching Capability

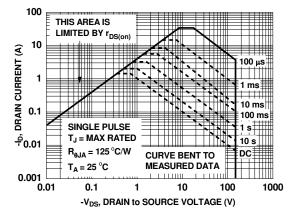


Figure 11. Forward Bias Safe Operating Area

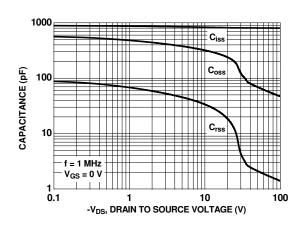


Figure 8. Capacitance vs Drain to Source Voltage

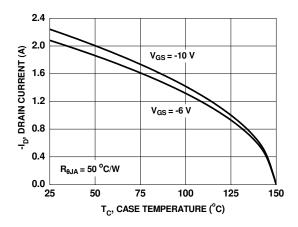


Figure 10. Maximum Continuous Drain Current vs Ambient Temperature

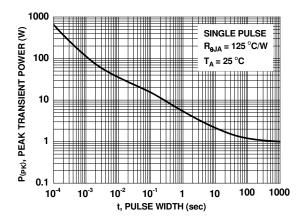
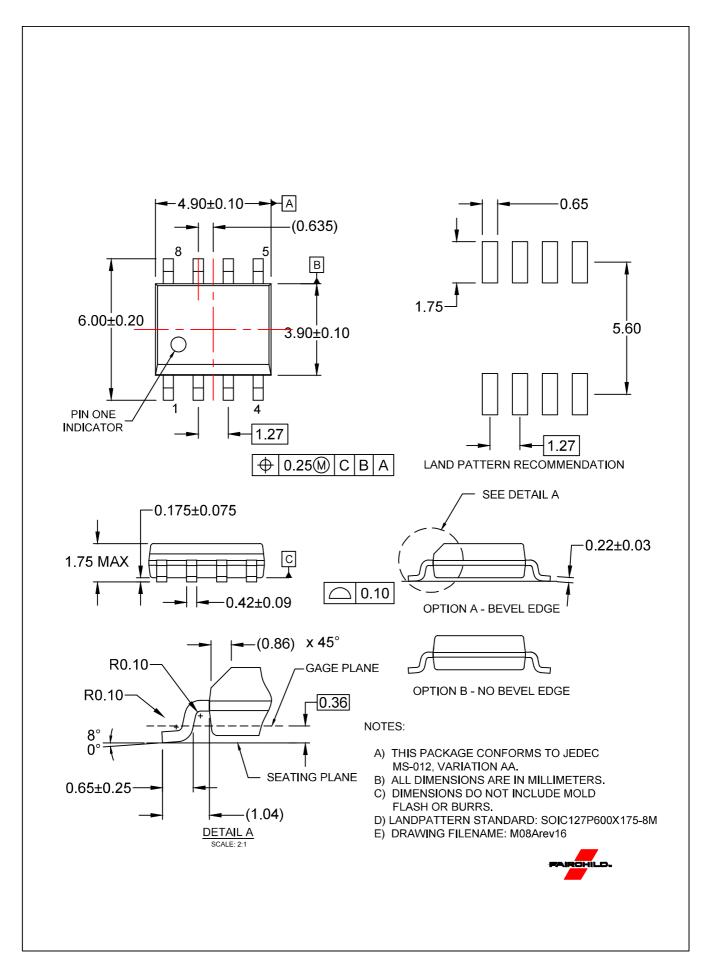


Figure 12. Single Pulse Maximum Power Dissipation



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